The First IEEE International Workshop on Electronic Design, Test and Applications (DELTA 2002)

Michel Renovell, Seiji Kajihara, Ibrahim Ai-Bahadly, Serge Demidenko

▶ To cite this version:

Michel Renovell, Seiji Kajihara, Ibrahim Ai-Bahadly, Serge Demidenko (Dir.). The First IEEE International Workshop on Electronic Design, Test and Applications (DELTA 2002). IEEE Computer Society, 2002, 0-7695-1453-7. ⟨lirmm-00268664⟩

HAL Id: lirmm-00268664

https://hal-lirmm.ccsd.cnrs.fr/lirmm-00268664v1

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Proceedings

The First IEEE International Workshop on
Electronic Design, Test and Applications

Δ'2002

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Proceedings

The First IEEE International Workshop on
Electronic Design, Test and Applications
Δ'2002

29-31 January 2002
Christchurch, New Zealand

Edited by
M. Renovell, S. Kajihara, I. Al-Bahadly and S. Demidenko

Sponsored by
IEEE Computer Society Test Technology Technical Council (TTTC)
Massey University, New Zealand

In cooperation with
MOSIS, University of Southern California
SEMI—Semiconductor Equipment and Materials International
Tanner EDA—A Division of Tanner Research Inc.
University of Canterbury, New Zealand

With assistance from
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IEEE Computer Society Order Number PR01453
ISBN 0-7695-1453-7
ISBN 0-7695-1455-3 (microfiche)
Library of Congress Number 2001098179

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Editorial production by Anne Jacobs

Cover art production by Joe Daigle/Studio Productions

Printed in the United States of America by The Printing House

DELTA 2002

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